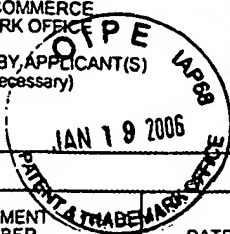
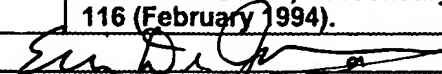
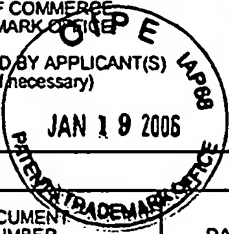
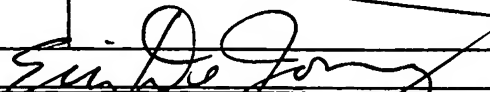


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|---|----|---|----------|--|-------|--------------------------------------|---------------------------------------|
| FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) | | | | ATTY DOCKET NO. 03560.003310 | | APPLICATION NO. 10/601,777 | |
|  | | | | APPLICANT Tadashi Okamoto et al. | | | |
| | | | | FILING DATE June 24, 2003 | | GROUP 1631 | |
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